

Search Notes

Application/Control No.

10/672,357

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

FU ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	708	4/19/2006	BT
438	709	4/19/2006	BT
438	717	4/19/2006	BT
438	725	4/19/2006	BT

INTERFERENCE SEARCHED

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438	708	4/19/2006	BT
438	709	4/19/2006	BT
438	717	4/19/2006	BT
438/725		4/19/2006	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	4/19/2006	BT